MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

1-33-07

MPS-U07

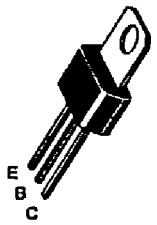
NOT RECOMMENDED FOR NEW DESIGNS

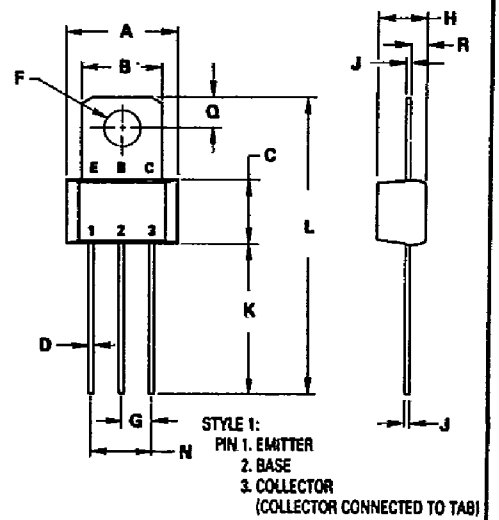
NPN SILICON ANNULAR AMPLIFIER TRANSISTOR

. . . designed for general-purpose, high-voltage amplifier and driver applications.

- High Collector-Emitter Breakdown Voltage — $V_{(BR)CEO}$ = 100 Vdc (Min) @ I_C = 1.0 mAdc
- High Power Dissipation — P_D = 10 W @ T_C = 25°C
- Complement to PNP MPS-U57

NPN SILICON AMPLIFIER TRANSISTOR





NOTE:
1. LEADS WITHIN 0.15 mm(0.006) TOTAL OF TRUE POSITION AT CASE, AT MAXIMUM MATERIAL CONDITION.

DIM	MILLIMETERS MIN	MILLIMETERS MAX	INCHES MIN	INCHES MAX
A	9.14	9.53	0.360	0.375
B	6.60	7.24	0.260	0.285
C	5.41	5.66	0.213	0.223
D	0.38	0.53	0.015	0.021
F	3.18	3.33	0.125	0.131
G	2.54 BSC		0.100 BSC	
H	3.94	4.19	0.155	0.165
J	0.36	0.41	0.014	0.016
K	11.63	12.70	0.458	0.500
L	24.58	25.53	0.968	1.005
N	5.08 BSC		0.200 BSC	
Q	2.39	2.69	0.094	0.106
R	1.14	1.40	0.045	0.055

CASE 152-02

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	100	Vdc
Collector-Base Voltage	V_{CB}	100	Vdc
Emitter-Base Voltage	V_{EB}	4.0	Vdc
Collector Current — Continuous	I_C	2.0	Adc
Total Power Dissipaton @ T_A = 25°C Derate above 25°C	P_D	1.0 8.0	Watt mW/°C
Total Power Dissipaton @ T_C = 25°C Derate above 25°C	P_D	10 80	Watts mW/°C
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-55 to +150	°C

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	$R_{\theta JC}$	12.5	°C/W
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	125	°C/W

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Collector-Emitter Breakdown Voltage (1) (I_C = 1.0 mAdc, I_B = 0)	$V_{(BR)CEO}$	100	–	–	Vdc
Emitter-Base Breakdown Voltage (I_E = 100 μAdc, I_C = 0)	$V_{(BR)EBO}$	4.0	–	–	Vdc
Collector Cutoff Current (V_{CB} = 80 Vdc, I_E = 0)	I_{CBO}	–	–	100	nAdc
ON CHARACTERISTICS					
DC Current Gain (1) (I_C = 50 mAdc, V_{CE} = 1.0 Vdc)	h_{FE}	60	110	–	–
(I_C = 250 mAdc, V_{CE} = 1.0 Vdc)		30	65	–	
(I_C = 500 mAdc, V_{CE} = 1.0 Vdc)		–	33	–	
Collector-Emitter Saturation Voltage (1) (I_C = 250 mAdc, I_B = 10 mAdc)	$V_{CE(sat)}$	–	0.18	0.4	Vdc
(I_C = 250 mAdc, I_B = 25 mAdc)		–	0.1	–	
Base-Emitter On Voltage (1) (I_C = 250 mAdc, V_{CE} = 5.0 Vdc)	$V_{BE(on)}$	–	0.76	1.2	Vdc
SMALL-SIGNAL CHARACTERISTICS					
Current-Gain–Bandwidth Product (1) (I_C = 250 mAdc, V_{CE} = 5.0 Vdc, f = 100 MHz)	f_T	50	150	–	MHz
Output Capacitance (V_{CB} = 10 Vdc, I_E = 0, f = 100 kHz)	C_{ob}	–	6.0	12	pF

(1)Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%.

FIGURE 1 – DC CURRENT GAIN

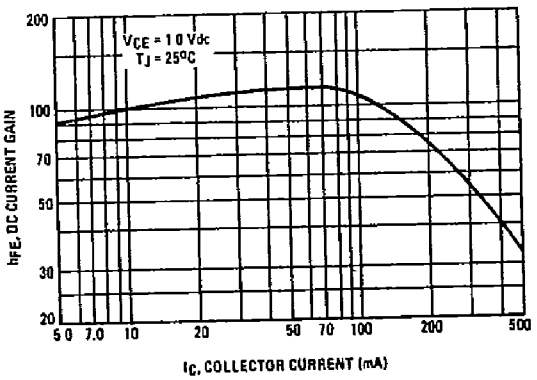


FIGURE 2 – "ON" VOLTAGES

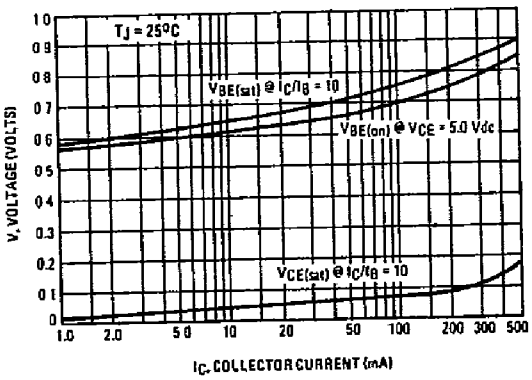


FIGURE 3 – DC SAFE OPERATING AREA

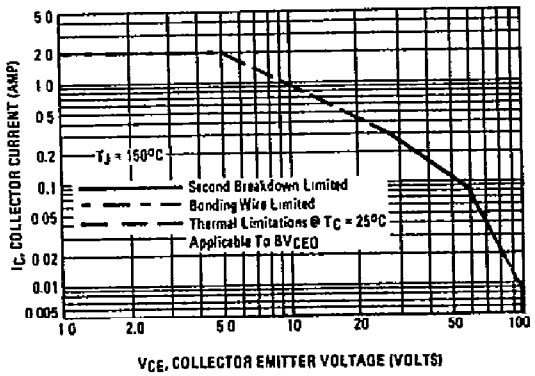
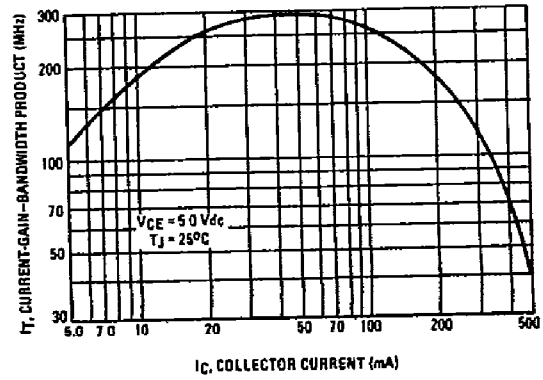


FIGURE 4 – CURRENT-GAIN–BANDWIDTH PRODUCT



There are two limitations on the power handling ability of a transistor: junction temperature and second breakdown. Safe operating area curves indicate $I_C - V_{CE}$ limits of the transistor that must be observed for reliable operation; i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 3 is based on $T_{J(pk)}$ = 150°C; T_C is variable depending on conditions. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.